



SMD Comm X8G HT150C Flex, Ceramic, 510 pF, 10%, 200 VDC, X8G, SMD, MLCC, High Temperature, Ultra-Stable, 0603, 0.4 mm



General Information	
Series	SMD Comm X8G HT150C Flex
Style	SMD Chip
Description	SMD, MLCC, High Temperature, Ultra-Stable
Features	High Temperature, Ultra-Stable
RoHS	Yes
Termination	Flexible Termination
Marking	No
AEC-Q200	No
Typical Component Weight	4.6 mg
Shelf Life	78 Weeks
MSL	1

Dimensions	
Chip Size	0603
L	1.6mm +/-0.17mm
W	0.8mm +/-0.15mm
Т	0.8mm +/-0.15mm
S	0.4mm MIN
В	0.45mm +/-0.15mm

L	1.0111111 +/ -0.1/111111	Measurement Condition	TIVINZ I.OVITIS
W	0.8mm +/-0.15mm	Tolerance	10%
Т	0.8mm +/-0.15mm	Voltage DC	200 VDC
S	0.4mm MIN	Dielectric Withstanding Voltage	500 VDC
В	0.45mm +/-0.15mm	Temperature Range	-55/+150°C
		Temp. Coefficient	X8G
Packaging Specifications		Capacitance Change with	30 ppm/C, 1MegaHz 1.0
Packaging	T&R, 330mm, Paper Tape	Reference to +25°C and 0 VDC Applied (TCC)	
Packaging Quantity	15000	D' i d'e Feder	0.10/ 1.1411 1.03/

Specifications	
Capacitance	510 pF
Measurement Condition	1 MHz 1.0Vrms
Tolerance	10%
Voltage DC	200 VDC
Dielectric Withstanding Voltage	500 VDC
Temperature Range	-55/+150°C
Temp. Coefficient	X8G
Capacitance Change with Reference to +25°C and 0 VDC Applied (TCC)	30 ppm/C, 1MegaHz 1.0Vrms
Dissipation Factor	0.1% 1 MHz 1.0Vrms
Aging Rate	0% Loss/Decade Hour: Referee Time is 1000 Hours
Insulation Resistance	100 GOhms

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